Pictured is a Thick Step Height Standard with chrome coating and showing the step height bar in the center. There are also V-Track and Pitch Array diagnostic tools featured.

Product Description for Step Height Standards larger than 1 µm
The actual calibration area consists of a negative feature (trench) 1 mm wide and 2.5 mm in length and is clearly marked with pointers. Two additional pitch structures form a test track for stylus dynamics and scan speed set-up, while two "V" shaped features can be used to determine the integrity and cleanliness of the stylus. The standard is coated with a conformal layer of Chromium 90 nm thick to ensure high reflectivity.

Product Specifications
- Nominal Step Heights:
  8 nm, 18 nm, 44 nm, 88 nm, 180 nm, 450 nm, 940 nm, 1.8 µm, 4.5 µm, 8.0 µm, 14.5 µm, 19.5 µm, 24 µm, 50 µm
- Substrate Size
  25 mm x 25 mm x 3.0 mm
- Traceability
  Traceable to SI units through NIST Calibrated Specimens